

# FAIRCHILD

SEMICONDUCTOR

November 1992 Revised January 1999

# 74ABT543 Octal Registered Transceiver with 3-STATE Outputs

# **General Description**

The ABT543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow.

### Features

- Back-to-back registers for storage
- Bidirectional data path
- A and B outputs have current sourcing capability of 32 mA and current sinking capability of 64 mA

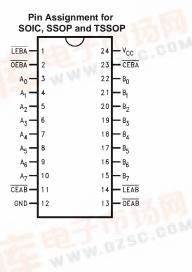
- Separate controls for data flow in each direction
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

# Ordering Code:

	and the second second	
Order Number	Package Number	Package Description
74ABT543CSC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT543CMSA	MSA24	24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT543CMTC	MTC24	24-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

# **Connection Diagram**



# Pin Descriptions

Pin Names	Description
OEAB, OEBA	Output Enable Inputs
LEAB, LEBA	Latch Enable Inputs
CEAB, CEBA	Chip Enable Inputs
A <sub>0</sub> -A <sub>7</sub>	Side A Inputs or 3-STATE Outputs
B <sub>0</sub> -B <sub>7</sub>	Side B Inputs or 3-STATE Outputs





# **Functional Description**

The ABT543 contains two sets of D-type latches, with separate input and output controls for each. For data flow from A to B, for example, the A to B Enable (CEAB) input must be low in order to enter data from the A Port or take data from the B Port as indicated in the Data I/O Control Table. With CEAB low, a low signal on (LEAB) input makes the A to B latches transparent; a subsequent low to high transition of the LEAB line puts the A latches in the storage mode and their outputs no longer change with the A inputs. With CEAB and OEAB both low, the B output buffers are active and reflect the data present on the output of the A latches. Control of data flow from B to A is similar, but using the CEBA, LEBA and OEBA.

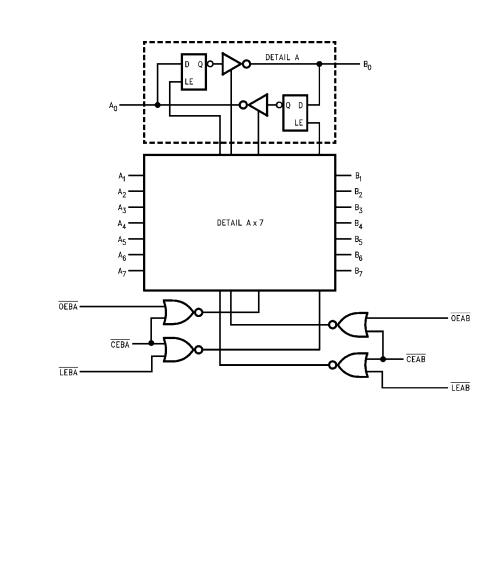
# Data I/O Control Table

	Inputs		Latch Status	Output Buffers
CEAB	CEABLEABOEABHXXXHX			
Н	Х	Х	Latched	HIGH Z
Х	н	Х	Latched	—
L	L	Х	Transparent	—
Х	Х	н	_	HIGH Z
L	Х	L	_	Driving

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial

# Logic Diagram



# Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	-55°C to +150°C
V <sub>CC</sub> Pin Potential to	
Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disable or Power-Off State	-0.5V to +5.5V
in the HIGH State	–0.5V to V <sub>CC</sub>
Current Applied to Output	
in LOW State (Max)	twice the rated $I_{OL}$ (mA)

DC Latchup Source Current Over Voltage Latchup (I/O)

# Recommended Operating Conditions

Free Air Ambient Temperature	$-40^{\circ}C$ to $+85^{\circ}C$
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns
Clock Input	100 mV/ns
Note 1: Absolute maximum ratings are values may be damaged or have its useful life impa under these conditions is not implied.	

74ABT543

–500 mA 10V

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

# **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
VIL	Input LOW Voltage	0.8			V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V		I <sub>IN</sub> = -18 mA (Non I/O Pins)
V <sub>OH</sub>	Output HIGH Voltage	2.5					$I_{OH} = -3 \text{ mA}, (A_n, B_n)$
		2.0					I <sub>OH</sub> = -32 mA, (A <sub>n</sub> , B <sub>n</sub> )
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	$I_{OL} = 64 \text{ mA}, (A_n, B_n)$
VID	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA, (Non-I/O Pins)
							All Other Pins Grounded
I <sub>IH</sub>	Input HIGH Current			1	μA	Max	V <sub>IN</sub> = 2.7V (Non-I/O Pins) (Note 3)
				1			V <sub>IN</sub> = V <sub>CC</sub> (Non-I/O Pins)
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μA	Max	V <sub>IN</sub> = 7.0V (Non-I/O Pins)
I <sub>BVIT</sub>	Input HIGH Current			100	μA	Max	$V_{IN} = 5.5V (A_n, B_n)$
	Breakdown Test (I/O)						
IIL	Input LOW Current			-1	μA	Max	V <sub>IN</sub> = 0.5V (Non-I/O Pins) (Note 3)
				-1			V <sub>IN</sub> = 0.0V (Non-I/O Pins)
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			10	μA	0V–5.5V	$V_{OUT} = 2.7V (A_n, B_n);$
							$\overline{OEAB}$ or $\overline{CEAB} = 2V$
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			-10	μA	0V-5.5V	$V_{OUT} = 0.5V (A_n, B_n);$
							$\overline{OEAB}$ or $\overline{CEAB} = 2V$
los	Output Short-Circuit Current	-100		-275	mA	Max	$V_{OUT} = 0V (A_n, B_n)$
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μA	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
I <sub>ZZ</sub>	Bus Drainage Test			100	μA	0.0V	$V_{OUT} = 5.5V (A_n, B_n);$
							All Others GND
I <sub>CCLH</sub>	Power Supply Current			50	μA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			50	μA	Max	Outputs 3-STATE
							All Others at V <sub>CC</sub> or GND
ICCT	Additional I <sub>CC</sub> /Input			2.5	mA	Max	$V_I = V_{CC} - 2.1V$
							All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load						Outputs Open, CEAB
	(Note 5)			0.18	mA/MHz	Max	and $\overline{OEAB} = GND$ , $\overline{CEBA} = V_{CC}$ , One Bit Toggling,
							50% Duty Cycle, (Note 4)

Note 4: For 8-bit toggling.  $I_{CCD} < 1.4$  mA/MHz.

Note 5: Guaranteed, but not tested.

က
4
Ľ
Б
₹
4
~

# **DC Electrical Characteristics**

(SOIC Pad	kage)						
							Conditions
Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	$C_L = 50 \text{ pF},$
							$\mathbf{R}_{\mathbf{L}} = 500\Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.7	1.0	V	5.0	$T_A = 25^{\circ}C$ (Note 6)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.2	-0.8		V	5.0	$T_A = 25^{\circ}C$ (Note 6)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.5	3.0		V	5.0	$T_A = 25^{\circ}C$ (Note 7)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.0	1.7		V	5.0	T <sub>A</sub> = 25°C (Note 8)
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		0.7	0.9	V	5.0	T <sub>A</sub> = 25°C (Note 8)

Note 6: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

Note 7: Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

Note 8: Max number of data inputs (n) switching. n - 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>ILD</sub>). Guaranteed, but not tested.

# **AC Electrical Characteristics**

(SOIC and SSOP Packages)

Symbol	Parameter		$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = -40^{\circ}$ $V_{CC} = 4$ $C_L =$	Units	
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.5	3.1	4.8	1.5	4.8	ns
t <sub>PHL</sub>	A <sub>n</sub> to B <sub>n</sub> or B <sub>n</sub> to A <sub>n</sub>	1.5		4.8	1.5	4.8	
t <sub>PLH</sub>	Propagation Delay						
t <sub>PHL</sub>	$\overline{\text{LEAB}}$ to $B_n$ , $\overline{\text{LEBA}}$ to $A_n$	1.6	3.4	5.3	1.6	5.3	ns
	$\overline{\text{OEBA}}$ or $\overline{\text{OEAB}}$ to $A_n$ or $B_n$	1.6		5.3	1.6	5.3	
t <sub>PZH</sub>	Enable Time						
t <sub>PZL</sub>	$\overline{\text{LEAB}}$ to $B_n$ , $\overline{\text{LEBA}}$ to $A_n$	1.5	3.6	5.8	1.5	5.8	ns
	$\overline{\text{OEBA}}$ or $\overline{\text{OEAB}}$ to $A_n$ or $B_n$	1.5		5.8	1.5	5.8	
t <sub>PHZ</sub>	Disable Time	2.0	4.0	6.5	2.0	6.5	ns
t <sub>PLZ</sub>	$\overline{\text{CEBA}}$ or $\overline{\text{CEAB}}$ to $A_n$ or $B_n$	2.0		6.5	2.0	6.5	

#### **AC Operating Requirements** (SOIC and SSOP Packages)

Symbol	Parameter	V <sub>CC</sub> =	+25°C - +5.0V 50 pF	V <sub>CC</sub> = 4	C to +85°C .5V–5.5V 50 pF	Units
		Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	1.5		1.5		ns
t <sub>S</sub> (L)	A <sub>n</sub> or B <sub>n</sub> to LEBA or LEAB	1.5		1.5		
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	1.0		1.0		ns
t <sub>H</sub> (L)	A <sub>n</sub> or B <sub>n</sub> to LEBA or LEAB	1.0		1.0		
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	1.5		1.5		ns
t <sub>S</sub> (L)	$A_n$ or $B_n$ to $\overline{CEAB}$ or $\overline{CEBA}$	1.5		1.5		
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	1.3		1.3		ns
t <sub>H</sub> (L)	$A_n$ or $B_n$ to $\overline{CEAB}$ or $\overline{CEBA}$	1.3		1.3		
t <sub>W</sub> (L)	Pulse Width, LOW	3.0		3.0		ns

# **Extended AC Electrical Characteristics**

~
4
Ъ
2
w
-
S
à
i.>

(SOIC Pa	$T_{\Delta} = -40^{\circ}C \text{ to } +85^{\circ}C$				$T_A = -40^\circ$	$T_{\Delta} = -40^{\circ}C \text{ to } +85^{\circ}C$		C to +85°C	
Symbol	-	$V_{CC} = 4.5V - 5.5V$ $C_1 = 50 \text{ pF}$			$V_{CC} = 4.5V - 5.5V$ $C_1 = 250 \text{ pF}$		$V_{CC} = 4.5V - 5.5V$ $C_1 = 250 \text{ pF}$		Units
	Parameter	8 Oı	8 Outputs Switching (Note 9)			1 Output Switching (Note 10)		8 Outputs Switching (Note 11)	
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>TOGGLE</sub>	Max Toggle Frequency		100						MHz
t <sub>PLH</sub>	Propagation Delay	1.5		6.2	2.0	7.5	2.5	10.0	ns
t <sub>PHL</sub>	A <sub>n</sub> to B <sub>n</sub> or B <sub>n</sub> to A <sub>n</sub>	1.5		6.2	2.0	7.5	2.5	10.0	
t <sub>PLH</sub>	Propagation Delay	1.5		6.5	2.0	8.0	2.5	10.5	ns
t <sub>PHL</sub>	LEAB to B <sub>n</sub> , LEBA to A <sub>n</sub>	1.5		6.5	2.0	8.0	2.5	10.5	
t <sub>PZH</sub>	Output Enable Time								
t <sub>PZL</sub>	$\overline{OEBA}$ or $\overline{OEAB}$ to $A_n$ or $B_n$	1.5		7.5	2.0	8.5	2.5	11.0	ns
	$\overline{\text{CEBA}}$ or $\overline{\text{CEAB}}$ to $A_n$ or $B_n$	1.5		7.5	2.0	8.5	2.5	11.0	
t <sub>PHZ</sub>	Output Disable Time								
t <sub>PLZ</sub>	OEBA or OEAB to An or Bn	1.5		8.5	(Not	te 12)	(Not	e 12)	ns
	$\overline{CEBA}$ or $\overline{CEAB}$ to $A_n$ or $B_n$	1.5		8.5					

Note 9: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 10: This specification is guaranteed but not tested. The limits represent propagation delay with 250pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 11: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 12: The 3-STATE delay times are dominated by the RC network (500Ω, 250 pF) on the output and has been excluded from the datasheet

#### Skew

Symbol	Parameter	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 50 \text{ pF}$ 8 Outputs Switching (Note 13)	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 250 \text{ pF}$ 8 Outputs Switching (Note 14)	Units
toshl	Pin to Pin Skew	1.0	<b>Max</b> 2.0	ns
(Note 15)	HL Transitions	1.0	2.0	10
t <sub>OSLH</sub> (Note 15)	Pin to Pin Skew LH Transitions	1.3	2.0	ns
t <sub>PS</sub> (Note 16)	Duty Cycle LH–HL Skew	2.0	4.0	ns
t <sub>OST</sub> (Note 15)	Pin to Pin Skew LH/HL Transitions	2.0	4.0	ns
t <sub>PV</sub> (Note 17)	Device to Device Skew LH/HL Transitions	2.5	4.5	ns

Note 13: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 14: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 15: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW ( $t_{OSHL}$ ), LOW-to-HIGH ( $t_{OSLH}$ ), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW ( $t_{OST}$ ). This specification is guaranteed but not tested.

Note 16: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. Note 17: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not

Note 17: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not tested.

